

# 3.75 kV<sub>RMS</sub>, 4.5-A/9-A Isolated Single Channel Gate Driver

# **Product Preview**

# NCV51152

The NCV51152 is a family of isolated single–channel gate driver with 4.5–A/9–A source and sink peak current respectively. They are designed for fast switching to drive power MOSFETs, and SiC MOSFET power switches. The NCV51152 offers short and matched propagation delays. The NCV51152xA provides a split output that controls the rise and fall times individually. The NCV51152xB has its  $V_{\rm CC}$  UVLO referenced to GND2 to get a true UVLO.

The NCV51152 is available in a 4 mm SOIC-8 package and can support isolation voltage up to 3.75 kV  $_{RMS}$ .

The NCV51152 offers other important protection function such as independent under-voltage lockout for both-side driver.

#### **Features**

- Feature Options
  - Separated Outputs (NCV51152xA)
  - Wide Bias Voltage Range Including Negative V<sub>EE</sub> and V<sub>CC</sub> UVLO Referenced to GND2 (NCV51152xB)
- 3-V to 20-V Input Supply Voltage
- Output Supply Voltage from 6.5 V to 30 V with 5-V and 8-V for MOSFET, 12-V and 17-V for SiC, Threshold
- 4.5-A Peak Source, 9-A Peak Sink Output Current Capability
- 200 V/ns dV/dt Immunity
- Negative 5–V Handling Capability on Input Pins
- Propagation Delay Typical 36 ns with
  - 5 ns Max Delay Matching
- Gate Clamping During Short Circuit (NCV51152xA)
- AEC-Q100 Qualified for Automotive Application Requirements
- Isolation & Safety
  - ◆ 3.75 kV<sub>RMS</sub> Isolation for 1 Minute (per UL1577 Requirements) (Planned)
  - CQC Certification per GB4943.1–2011 (Planned)
  - SGS FIMO Certification per IEC 62386-1 (Planned)

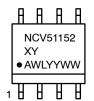
#### **Typical Applications**

- On-board Chargers
- xEV DC-DC Converters
- Traction Inverters
- Charging Stations

This document contains information on a product under development. **onsemi** reserves the right to change or discontinue this product without notice.



#### **MARKING DIAGRAM**



NCV51152 = Specific Device Code

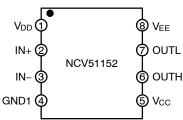
X = A or B or C or D for UVLO Option Y = A: Split Output, or B: VEE\_GND2 for

True UVLO

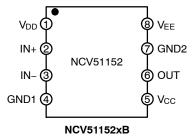
A = Assembly Location

WL = Wafer Lot YY = Year WW = Work Week

#### **PIN CONNECTIONS**



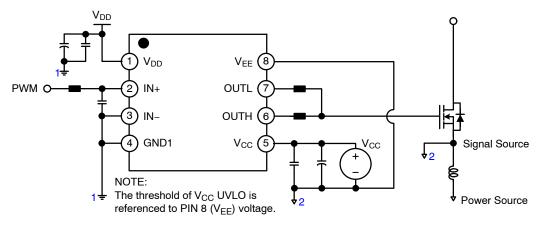
NCV51152xA



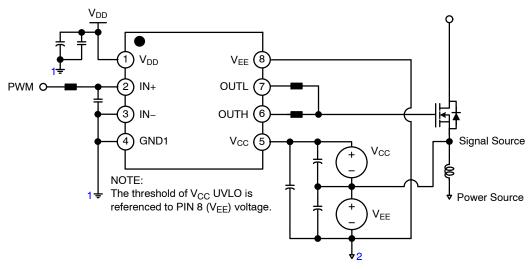
#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 22 of this data sheet.

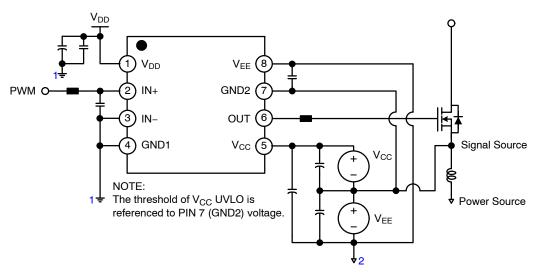
# **TYPICAL APPLICATION CIRCUIT**



(a) Split Output for variant A



(b) Split Output and external negative bias for variant A



(c) External negative bias for variant B

Figure 1. Typical Application Schematic

# **FUNCTIONAL BLOCK DIAGRAM**

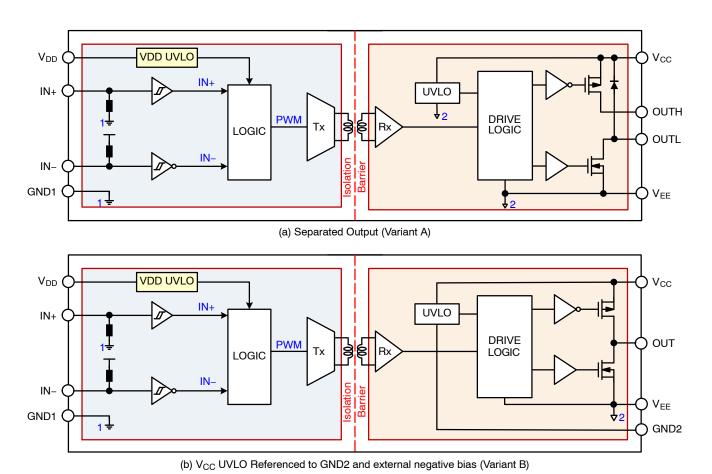


Figure 2. Simplified Block Diagram

# **PIN CONNECTIONS**

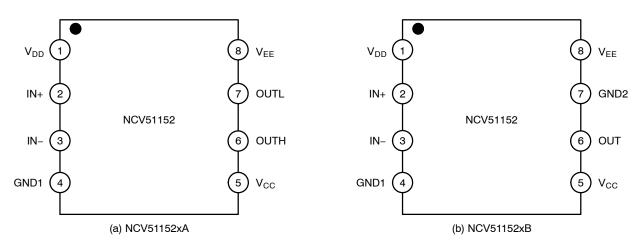


Figure 3. Pin Connections – SOIC-8 NB (Top View)

# **PIN DESCRIPTION**

	Pin No.			
Pin Name	NCV51152xA	NCV51152xB	I/O	Description
V <sub>DD</sub>	1	1	Power	Input-side Supply Voltage. It is recommended to place a bypass capacitor from V <sub>DD</sub> to GND1.
IN+	2	2	Input	Non-inverting Logic Input with internal pull-down resistor to GND1.
IN-	3	3	Input	Inverting Logic Input with internal pull-up resistor to V <sub>DD</sub> .
GND1	4	4	Power	Ground Input-side. (all signals on input-side are referenced to this ground)
V <sub>CC</sub>	5	5	Power	Positive Output Supply Rail.
OUTH	6	6	Output	Gate Drive Pull-up Output.
OUTL	7	-	Output	Gate Drive Pull-down Output.
GND2	-	7	Power	Gate-drive common pin. Connect this pin to the MOSFET source. V <sub>CC</sub> UVLO with respect to GND2 for variant B.
V <sub>EE</sub>	8	8	Power	Negative output supply rail for variant B, and ground for variant A.

#### **INSULATION RATINGS**

Symbol	Parameter		Value	Unit
	Installation Classifications per DIN VDE 0110/1.89 Table 1 Rated	<150 V <sub>RMS</sub>	I–IV	
	Mains Voltage	<300 V <sub>RMS</sub>	I–IV	
		<450 V <sub>RMS</sub>	I–IV	
		<600 V <sub>RMS</sub>	I–IV	
		<1000 V <sub>RMS</sub>	1–111	
CTI	Comparative Tracking Index (DIN IEC 112/VDE 0303 Part 1)		600	
	Climatic Classification		40/125/21	
	Pollution Degree (DIN VDE 0110/1.89)		2	
$V_{PR}$	Input-to-Output Test Voltage, Method b, $V_{IORM} \times 1.875 = V_{PR}$ , 100 Test with $t_m = 1$ s, Partial Discharge < 5 pC	0% Production	2250	V <sub>PK</sub>
$V_{IORM}$	Maximum Repetitive Peak Isolation Voltage		1200	$V_{PK}$
$V_{IOWM}$	Maximum Working Voltage		870	$V_{RMS}$
$V_{IOTM}$	Maximum Transient Isolation Voltage		6300	$V_{PK}$
E <sub>CR</sub>	External Creepage	4.0	mm	
E <sub>CL</sub>	External Clearance	4.0	mm	
DTI	Insulation Thickness	17.3	μm	
R <sub>IO</sub>	Insulation Resistance at T <sub>S</sub> , V <sub>IO</sub> = 500 V		10 <sup>9</sup>	Ω

#### **SAFETY LIMITING VALUE**

Symbol	Parameter	Test Condition	Side	Value	Unit
PS	Safety Supply Power	$R_{\theta JA} = 120^{\circ}C/W, T_A = 25^{\circ}C, T_J = 150^{\circ}C$	INPUT	0.21	W
			OUTPUT	1.04	W
			TOTAL	1.25	W
T <sub>S</sub>	Safety Temperature			150	°C

## **MAXIMUM RATINGS**

Symbol		Parameter	Min	Max	Unit
V <sub>DD</sub> to G	ND1	Power Supply Voltage – Input Side (Note 2)	-0.3	25	V
V <sub>CC</sub> – GI	ND2	Positive Supply Voltage – Driver Side	-0.3	33	V
VEE – GI	ND2	Negative Supply Voltage for Only B Version	-18	0.3	V
V <sub>CC</sub> – V	EE	Differential Supply Voltage – Driver Side (Note 3)	-0.3	33	V
OUT to \	/EE	Driver Output Voltage (Note 3)	V <sub>EE</sub> - 0.3	V <sub>CC</sub> + 0.3	V
OUT to V Transient for 200	,		V <sub>EE</sub> - 2	V <sub>CC</sub> + 0.3	V
IN+, and	IN-	Input Signal Voltages (Note 2)	-5	V <sub>DD</sub> + 0.3	V
TJ		Junction Temperature	-40	+150	°C
T <sub>S</sub>		Storage Temperature	-65	+150	°C
Electrostatic	HBM (Note 5)	Human Body Model	-	2	kV
Discharge Capability	CDM (Note 5)	Charged Device Model	-	1	kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe

- Operating parameters.

- All voltage values are given with respect to GND1 pin.
   All voltage values are given with respect to VEE pin.
   This parameter verified by design and bench test, not tested in production.
- This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per AEC-Q100-002 (EIA/JESD22-A114)

  - ESD Charged Device Model tested per AEC-Q100-011 (EIA/JESD22-C101) Latch up Current Maximum Rating: ≤100 mA per JEDEC standard: JESD78F.

#### THERMAL CHARACTERISTICS

Symbol	Parameter	Min	Max	Unit
$\theta_{\sf JA}$	Secondary Thermal Resistance of Junction-Air (Note 6)	Type-A (Note 7)	100	°C/W
		Type-B (Note 8)	120	
$\theta_{JT}$	Thermal Characterization Parameter Junction-Case Top	Type-A (Note 7)	8	
		Type-B (Note 8)	8	
$P_{D}$	Secondary Power Dissipation (Note 6)	Type-A (Note 7)	1.25	W
		Type-B (Note 8)	1.04	

- 6. Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.
- 7. As specified for a reference layout shown in Figure 4. The DUT is mounted on a 60 x 40 x 1.6 mm FR4 substrate with an additional heat spreading copper of 240 mm²/300 mm² (Primary/Secondary). The copper thickness is 1 oz and test conditions is under natural convection or zero air flow.

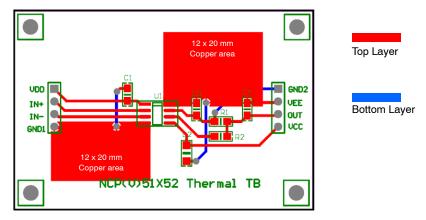


Figure 4. Reference Layout for the Type-A

8. As specified for a reference layout shown in Figure 5. The DUT is mounted on a 60 x 40 x 1.6mm FR4 substrate with an additional heat spreading copper of 240 mm²/300 mm² (Primary/Secondary). The copper thickness is 1oz and test conditions is under natural convection or zero air flow.

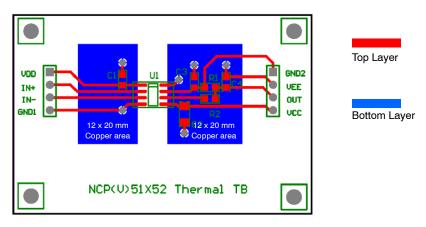


Figure 5. Reference Layout for the Type-A

#### RECOMMENDED OPERATING CONDITIONS

Symbol	Rating			Max	Unit
$V_{DD}$	Power Supply Voltage – Input Side		3.0	20	V
V <sub>CC</sub>	Power Supply Voltage – Driver Side (Note 9)	ver Supply Voltage – Driver Side (Note 9) 5–V UVLO Version		30	V
		8-V UVLO Version	9.5	30	V
	12-V UVLO Version		13.5	30	V
		17-V UVLO Version	18.5	30	V
VEE – GND2	Negative Supply Voltage for only Variant B (NCV51152xB)	•	-15	0	V
V <sub>IN</sub>	Logic Input Voltage at Pins IN+, and IN-		0	$V_{DD}$	V
T <sub>A</sub>	Ambient Temperature	-40	+125	°C	
TJ	Junction Temperature		-40	+125	°C
CMTI	Common Mode Transient Immunity		200	=	kV/μs

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

#### **ISOLATION CHARACTERISTICS**

Symbol	Parameter	Condition	Value	Unit
V <sub>ISO,INPUT</sub> TO OUTPUT	Input to Output Isolation Voltage	$T_A=25^{\circ}C,$ Relative Humidity < 50%, t = 1.0 minute, $I_{I-O}$ $_{<}$ 30 $\mu A,$ 50 Hz (Note 10,11,12)	3750	V <sub>RMS</sub>
R <sub>ISO</sub>	Isolation Resistance	V <sub>I_O</sub> = 500 V (Note 10)	10 <sup>11</sup>	Ω

<sup>10.</sup> Device is considered a two-terminal device: pins 1 to 4 are shorted together and pins 5 to 8 are shorted together.

<sup>9.</sup> All V<sub>CC</sub> UVLO threshold voltages of the variant A and B are given with respect to V<sub>EE</sub> and GND2 pins respectively.

<sup>11.3,750</sup> V<sub>RMS</sub> for 1-minute duration is equivalent to 4,500 V<sub>RMS</sub> for 1-second duration for input to output isolation test, and Impulse Test > 10 ms; sample tested for between channel isolation test.

<sup>12.</sup> The input–output isolation voltage is a dielectric voltage rating per UL1577. It should not be regarded as an input–output continuous voltage rating. For the continuous working voltage rating, refer to equipment–level safety specification or DIN VDE V 0884–11 Safety and Insulation Ratings Table.

**ELECTRICAL CHARACTERISTICS** ( $V_{DD} = 5 \text{ V}, V_{CC} = 15 \text{ V}, \text{ or } 20 \text{ V} \text{ (}V_{EE} = 0 \text{ V for NCV51151xB)}$  (Note 15) for typical values  $T_J = T_A = 25^{\circ}\text{C}$ , for min/max values  $T_J = -40^{\circ}\text{C}$  to  $+125^{\circ}\text{C}$ , unless otherwise specified. (Note 15))

Symbol	Parameter	Condition	Min	Тур	Max	Unit
PRIMARY P	OWER SUPPLY SECTION (VDD)					
$I_{QVDD}$	V <sub>DD</sub> Quiescent Current	$V_{IN+} = V_{IN-} = 0 \text{ V}, V_{DD} = 5 \text{ V}$	500	715	1000	μΑ
		$V_{IN+} = V_{IN-} = 0 \text{ V}, V_{DD} = 15 \text{ V}$	600	870	1100	μΑ
		$V_{IN+} = V_{IN-} = V_{DD}, V_{DD} = 5 \text{ V}$	500	720	1000	μΑ
		V <sub>IN+</sub> = V <sub>IN-</sub> = V <sub>DD</sub> , V <sub>DD</sub> = 15 V	600	870	1100	μΑ
I <sub>VDD</sub>	V <sub>DD</sub> Operating Current	V <sub>IN+</sub> = V <sub>DD</sub> , V <sub>IN-</sub> = 0 V, V <sub>DD</sub> = 5 V	4.5	6.4	8.0	mA
		V <sub>IN+</sub> = V <sub>DD</sub> , V <sub>IN-</sub> = 0 V, V <sub>DD</sub> = 15 V	5.0	6.6	8.4	mA
		$f_{IN+} = 500 \text{ kHz}, C_{OUT} = 200 \text{ pF}, V_{DD} = 5 \text{ V}$	2.9	3.9	5.0	mA
		$f_{IN+} = 500 \text{ kHz}, C_{OUT} = 200 \text{ pF}, V_{DD} = 15 \text{ V}$	3.0	4.1	5.2	mA
V <sub>DDUV+</sub>	V <sub>DD</sub> Supply Under-Voltage Positive-Going Threshold	V <sub>DD</sub> = Sweep	2.7	2.8	2.9	V
$V_{DDUV-}$	V <sub>DD</sub> Supply Under-Voltage Negative-Going Threshold	V <sub>DD</sub> = Sweep	2.6	2.7	2.8	٧
V <sub>DDHYS</sub>	V <sub>DD</sub> Supply Under-Voltage Lockout Hysteresis	V <sub>DD</sub> = Sweep	-	0.1	-	٧
t <sub>VDDUV</sub>	Debounce Time (Note 16)		-	_	10	μS
SECONDAF	RY POWER SUPPLY SECTION					
I <sub>QVCC</sub>	V <sub>CC</sub> Quiescent Current	V <sub>IN+</sub> = V <sub>IN-</sub> = 0 V or 5 V, No Load	200	385	700	μΑ
		V <sub>IN+</sub> = 5 V, V <sub>IN-</sub> = 0 V, No Load	200	507	800	μΑ
I <sub>VCC</sub>	V <sub>CC</sub> Operating Current	$f_{IN+} = 500 \text{ kHz}, C_{OUT} = 200 \text{ pF}, V_{CC} = 15 \text{ V}$	3.0	4.2	5.0	mA
		$f_{IN+} = 500 \text{ kHz}, C_{OUT} = 200 \text{ pF}, V_{CC} = 20 \text{ V}$	3.7	5.2	6.2	mA
VCC UVLO	THRESHOLD (6-V UVLO VERSION)	•	•	•	•	
V <sub>CCUV+</sub>	V <sub>CC</sub> Supply Under-Voltage Positive-Going Threshold (Note 13)		5.7	6.0	6.4	V
V <sub>CCUV</sub> -	V <sub>CC</sub> Supply Under-Voltage Negative-Going Threshold		5.3	5.7	6.0	V
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		-	0.3	-	V
t <sub>VCCUV</sub>	UVLO Filter Debounce Time (Note 16)		-	-	10	μS
VCC UVLO	THRESHOLD (8-V UVLO VERSION)					
V <sub>CCUV+</sub>	V <sub>CC</sub> Supply Under-Voltage Positive-Going Threshold (Note 13)		8.2	8.7	9.2	V
V <sub>CCUV</sub> -	V <sub>CC</sub> Supply Under-Voltage Negative-Going Threshold		7.7	8.2	8.7	V
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		-	0.5	-	V
t <sub>VCCUV</sub>	UVLO Filter Debounce Time (Note 16)		-	_	10	μs
VCC UVLO	THRESHOLD (12-V UVLO VERSION)					
V <sub>CCUV+</sub>	V <sub>CC</sub> Supply Under-Voltage Positive-Going Threshold (Note 13)		11	12	13	٧
V <sub>CCUV</sub> -	V <sub>CC</sub> Supply Under-Voltage Negative-Going Threshold		10	11	12	V
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		-	1.0	_	V
t <sub>VCCUV</sub>	UVLO Filter Debounce Time (Note 16)		_	-	10	μs

**ELECTRICAL CHARACTERISTICS** ( $V_{DD} = 5 \text{ V}, V_{CC} = 15 \text{ V}, \text{ or } 20 \text{ V} \text{ (}V_{EE} = 0 \text{ V for NCV51151xB)} \text{ (Note 15) for typical values } T_J = T_A = 25^{\circ}\text{C}, \text{ for min/max values } T_J = -40^{\circ}\text{C to } +125^{\circ}\text{C}, \text{ unless otherwise specified. (Note 15)) (continued)}$ 

Symbol	Parameter	Condition	Min	Тур	Max	Unit
ACC NAFO .	THRESHOLD (17-V UVLO VERSION)					
V <sub>CCUV+</sub>	V <sub>CC</sub> Supply Under-Voltage Positive-Going Threshold (Note 13)		16	17	18	V
V <sub>CCUV</sub> -	V <sub>CC</sub> Supply Under-Voltage Negative-Going Threshold		15	16	17	٧
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		_	1.0	_	V
t <sub>VCCUV</sub>	UVLO Filter Debounce Time (Note 16)		-	_	10	μs
LOGIC INPU	IT SECTION (IN+, AND IN-)					
$V_{INH}$	High Level Input Voltage		1.4	1.63	2.0	V
V <sub>INL</sub>	Low Level Input Voltage		8.0	1.08	1.4	V
V <sub>INHYS</sub>	Input Logic Hysteresis		-	0.55	_	V
I <sub>IN+H</sub>	High Level Logic Input Bias Current at IN+	V <sub>IN+</sub> = 5 V	33	40	52	μΑ
I <sub>IN+L</sub>	Low Level Logic Input Bias Current at IN-	V <sub>IN+</sub> = GND1	-	_	1.0	μΑ
I <sub>IN-H</sub>	High Level Logic Input Bias Current at IN+	V <sub>IN</sub> _ = 5 V	-1.0	_	_	μΑ
I <sub>IN-L</sub>	Low Level Logic Input Bias Current at IN-	V <sub>IN</sub> = GND1	-52	-40	-33	μΑ
R <sub>IN</sub>	Logic Input Pull-Up/Down Resistance		95	125	155	kΩ
SHORT CIR	CUIT SECTION					
V <sub>CLP-OUT</sub>	Clamping Voltage, Sourcing (V <sub>OUTH</sub> –V <sub>CC</sub> or V <sub>OUT</sub> – V <sub>CC</sub> )	IN+ = High, IN- = Low, $t_{CLAMP}$ = 10 μs $t_{OUTH}$ or $t_{OUT}$ = 500 mA	-	0.7	1.75	V
	Clamping Voltage, Sinking (VEE - V <sub>OUTL</sub> or V <sub>EE</sub> - V <sub>OUT</sub> )	IN+ = Low, IN- = High, $t_{CLAMP}$ = 10 $\mu s$ I <sub>OUTH</sub> or I <sub>OUT</sub> = -500 mA	-	0.24	0.5	V
GATE DRIVI	E SECTION					
I <sub>OUT+</sub>	Source Peak Current (Note 16)	$V_{IN+} = 5 \text{ V}, \text{ PW} \leq 5  \mu\text{s}$	2.6	4.5	_	Α
I <sub>OUT</sub>	Sink Peak Current (Note 16)	$V_{IN+} = 0 \text{ V, PW} \le 5  \mu\text{s}$	7.0	9.0	-	Α
R <sub>OH</sub>	Output Resistance at High State	I <sub>OUTH</sub> = 100 mA	_	1.4	2.8	Ω
R <sub>OL</sub>	Output Resistance at Low State	I <sub>OUTL</sub> = 100 mA	-	0.5	1.0	Ω
V <sub>OH</sub>	High Level Output Voltage (V <sub>CC</sub> - V <sub>OUT</sub> )	I <sub>OUTH</sub> = 100 mA	-	140	280	mV
V <sub>OL</sub>	Low Level Output Voltage (V <sub>OUT</sub> - V <sub>EE</sub> )	I <sub>OUTL</sub> = 100 mA	_	50	100	mV

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### **DYNAMIC ELECTRICAL CHARACTERISTICS**

Symbol	Parameter	Condition	Min	Тур	Max	Unit
t <sub>PDON</sub>	Turn-On Propagation Delay from IN to OUT	C <sub>LOAD</sub> = 0 nF	20	36	55	ns
t <sub>PDOFF</sub>	Turn-Off Propagation Delay from IN to OUT		20	36	55	ns
t <sub>PWD</sub>	Pulse Width Distortion (t <sub>PDON</sub> - t <sub>PDOFF</sub> )		-5	_	5	ns
t <sub>SK(PP)</sub>	Propagation Part-to-part Skew (Note 17)		-20	_	20	ns
t <sub>VPOR to OUT</sub>	Power-up Delay from the V <sub>POR</sub> to Output (Note 17)	See the Figure 47	-	18	-	μs
t <sub>R</sub>	Turn-On Rise Time	C <sub>LOAD</sub> = 1.8 nF	_	12	22	ns
t <sub>F</sub>	Turn-Off Fall Time	C <sub>LOAD</sub> = 1.8 nF	_	8.3	22	ns
t <sub>PW</sub>	Minimum Input Pulse Width that Change Output State	C <sub>LOAD</sub> = 0 nF	-	15	35	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>13.</sup>All  $V_{CC}$  UVLO threshold voltages are given with respect to GND2 pin.

14. Performance guaranteed over the indicated operating temperature range by design and/or characterization tested at  $T_J = T_A = 25^{\circ}C$ .

15.  $V_{CC} = 15$  V is used for the test condition of 5–V, and 8–V UVLO,  $V_{CC} = 20$  V is used for 12–V and 17–V UVLO.

16. These parameters verified by bench test only and not tested in production

<sup>17.</sup> These parameters verified by bench test only and not tested in production

#### **INSULATION CHARACTERISTICS CURVES**

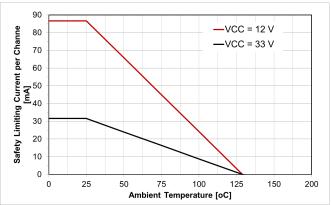


Figure 6. Thermal Derating Curve for Safety–related Limiting Current ( $\theta_{JA}$  = 110°C/W) (Note 7)

-VCC = 12 V

-VCC = 33 V

125

150

200

80

8afety Limiting Current per Channe [m4] 50 20 20 10 10

0

0

25

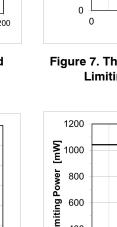


Figure 8. Thermal Derating Curve for Safety–related Limiting Current ( $\theta_{JA} = 130^{\circ}\text{C/W}$ ) (Note 8)

Ambient Temperature [oC]

100

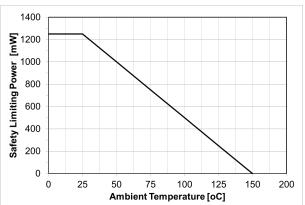


Figure 7. Thermal Derating Curve for Safety–related Limiting Power ( $\theta_{JA}$  = 110°C/W) (Note 7)

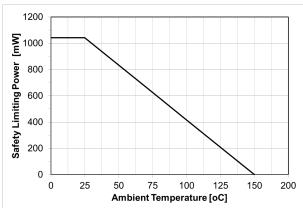
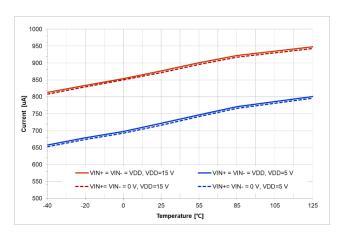


Figure 9. Thermal Derating Curve for Safety–related Limiting Power ( $\theta_{JA}$  = 130°C/W) (Note 8)

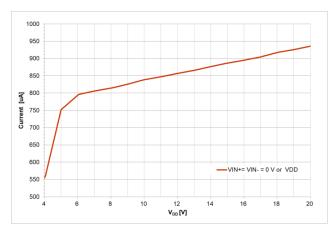
#### **TYPICAL CHARACTERISTICS**



8.0 7.5 7.0 5.5 5.0 4.5 4.0 3.5 3.0 VIN+ = VDD, VIN- = 0 V, VDD=15 V flN+=500 kHz, COUT=200 pF, VDD=15 V 2.5 --- VIN+ = VDD, VIN- = 0 V, VDD=5 V --- flN+=500 kHz, COUT = 200 pF, VDD=5 V 2.0 125 55 105 Temperature [°C]

Figure 10. V<sub>DD</sub> Quiescent Current vs. Temperature

Figure 11. V<sub>DD</sub> Quiescent Current vs. Temperature



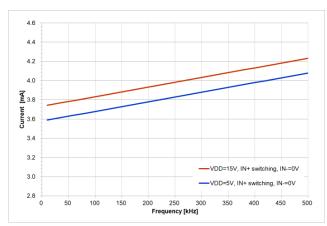
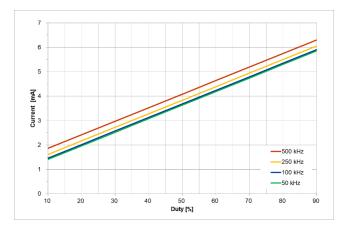


Figure 12.  $V_{DD}$  Quiescent Current vs.  $V_{DD}$ 

Figure 13. V<sub>DD</sub> Operating Current vs. Switching Frequency



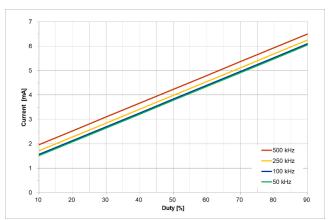


Figure 14.  $V_{DD}$  Operating Current vs. Duty ( $V_{DD} = 5 \text{ V}$ , IN+ Switching with Different Frequency, IN- = 0 V)

Figure 15. V<sub>DD</sub> Operating Current vs. Duty (V<sub>DD</sub> = 15 V, IN+ Switching with Different Frequency, IN- = 0 V)

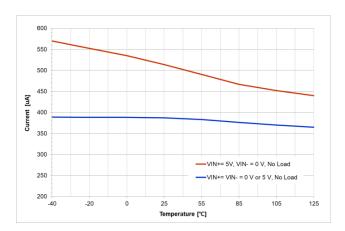


Figure 16. Quiescent V<sub>CC</sub> Supply Current vs. Temperature

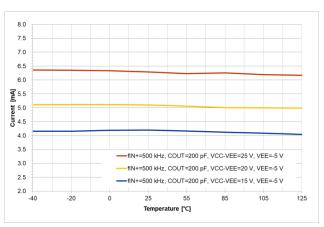


Figure 17. V<sub>CC</sub> Operating Current vs. Temperature

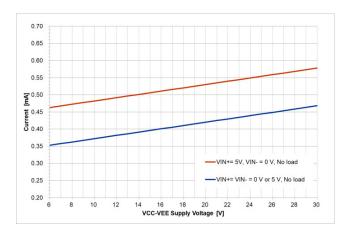


Figure 18. Quiescent  $V_{CC}$  Supply Current vs.  $V_{CC}$  Supply Voltage

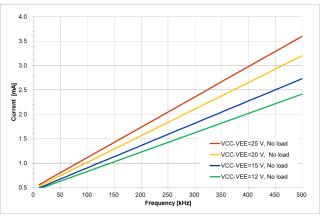


Figure 19.  $V_{CC}$  Operating Current vs. Switching Frequency (  $V_{CC}$  –  $V_{EE}$  = 12/15/20/25 V and No Load)

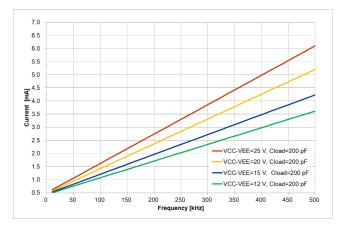


Figure 20.  $V_{CC}$  Operating Current vs. Switching Frequency (  $V_{CC}$  –  $V_{EE}$  = 12/15/20/25 V and  $C_{LOAD}$  = 200 pF)

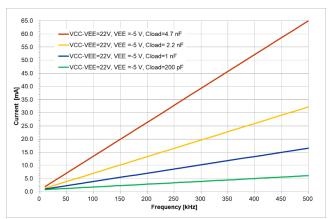


Figure 21.  $V_{CC}$  Operating Current vs. Switching Frequency ( $V_{CC} - V_{EE} = 20 \text{ V}$  and Different  $C_{LOAD}$ )

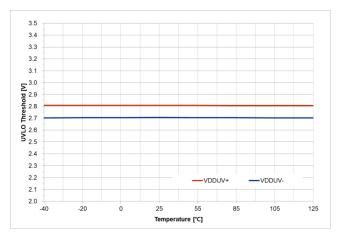
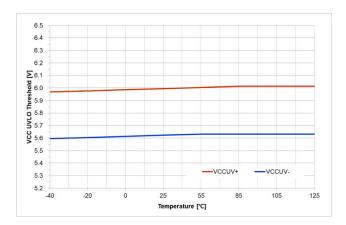


Figure 22.  $V_{\rm DD}$  UVLO vs. Temperature

Figure 23.  $V_{\rm DD}$  UVLO Hysteresis vs. Temperature



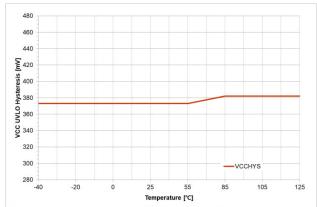
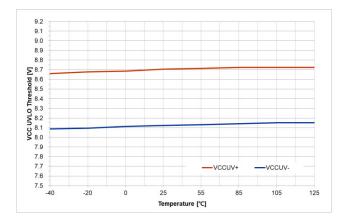


Figure 24.  $V_{CC}$  6-V UVLO Threshold vs. Temperature

Figure 25.  $V_{DD}$  6-V UVLO Hysteresis vs. Temperature



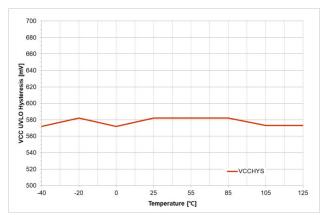


Figure 26. V<sub>CC</sub> 8-V UVLO Threshold vs. Temperature

Figure 27. V<sub>DD</sub> 8-V UVLO Hysteresis vs. Temperature

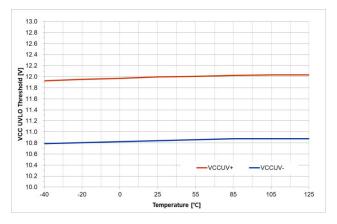
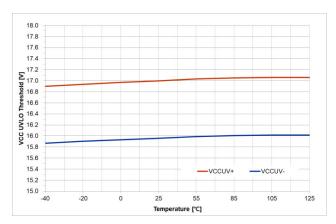


Figure 28. V<sub>CC</sub> 12-V UVLO Threshold vs. Temperature

Figure 29. V<sub>CC</sub> 12-V UVLO Hysteresis vs. Temperature



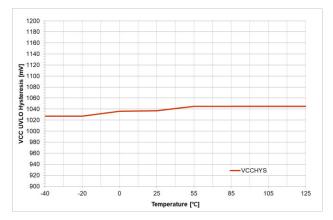
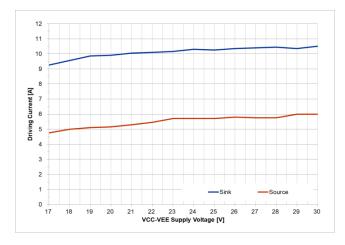


Figure 30. V<sub>CC</sub> 17-V UVLO Threshold vs. Temperature

Figure 31. V<sub>CC</sub> 17-V UVLO Hysteresis vs. Temperature



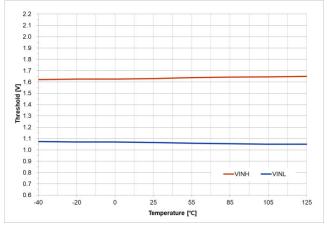
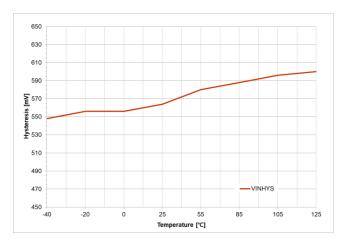


Figure 32. Figure 32. Output Current vs. V<sub>CC</sub> Supply Voltage

Figure 33. Input Logic Threshold vs. Temperature



129 **9** 126 Resistance 125 123 122 IN- Pull-up Resistance 121 120 55 -40 25 85 105 125 -20 Temperature [°C]

Figure 34. Input Logic Hysteresis vs. Temperature

Figure 35. Logic Input Pull-Up/Down Resistance vs.
Temperature

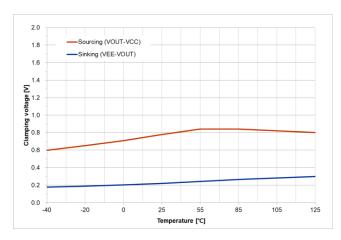
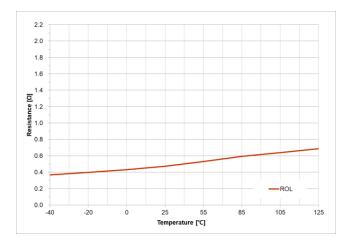


Figure 36. Clamping Voltage vs. Temperature

Figure 37. Output Resistance at High Sate vs. Temperature



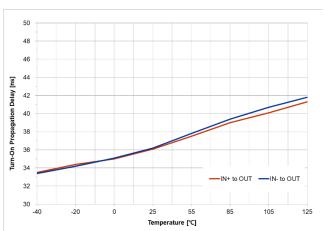


Figure 38. Output Resistance at Low Sate vs. Temperature

Figure 39. Turn-on Propagation Delay vs. Temperature (C<sub>LOAD</sub> = 0 nF)

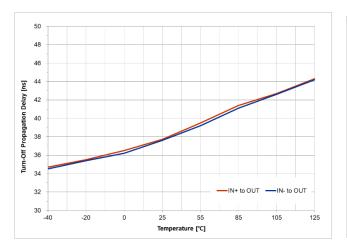


Figure 40. Turn-off Propagation Delay vs. Temperature (C<sub>LOAD</sub> = 0 nF)

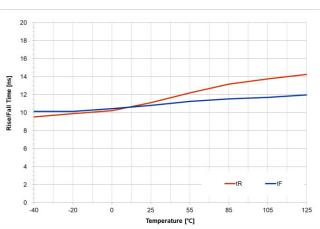


Figure 41. Rise/Fall Time vs. Temperature  $(C_{LOAD} = 1.8 \text{ nF})$ 

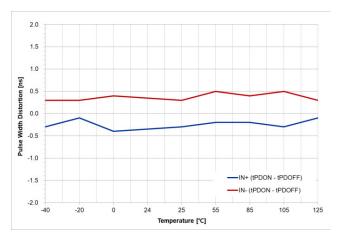


Figure 42. Pulse Width Distortion vs. Temperature (CLOAD = 0 nF)

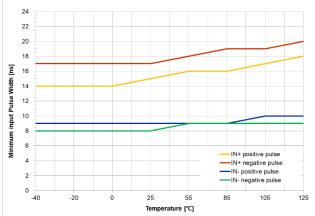


Figure 43. Minimum Input Pulse Width vs. Temperature

#### PARAMETER MEASUREMENT DEFINITION

#### **Switching Time Definitions**

Figure 44 shows the switching time waveforms definitions of the turn-on (tpDON) and turn-off (tpDOFF)

propagation delay times among the driver's input signal IN+ and output signal OUT. The typical values of the propagation delay (t<sub>PDON</sub>, t<sub>PDOFF</sub>), pulse width distortion (t<sub>PWD</sub>) and delay matching between channels times are specified in the electrical characteristics table.

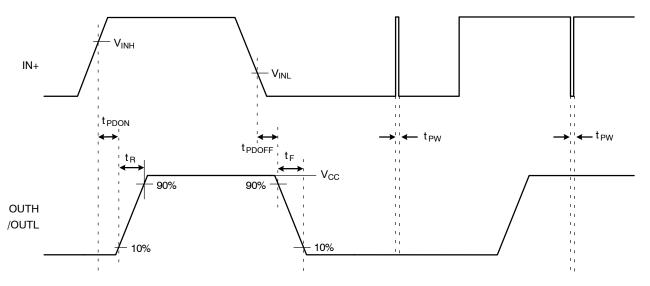


Figure 44. Switching Time Definition

#### **Input to Output Operation Definitions**

The NCV51152 provides important protection functions such as independent under-voltage lockout for gate driver. Figure 45 shows an overall input to output timing diagram. Under-Voltage Lockout protection on the primary- and

secondary-sides power supplies events in the *CASE-A*, *B* and *C* and the gate driver output (OUT) is immediately turn-off when two input signal (IN+ and IN-) are HIGH at same time in the *CASE-D*.

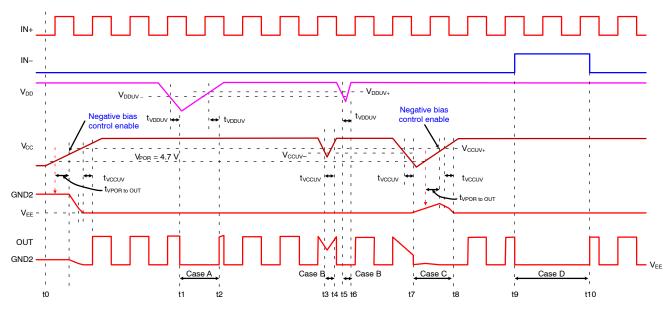


Figure 45. Overall Operating Waveforms Definitions

#### PROTECTION FUNCTION

The NCV51152 provides the protection features include Under-Voltage Lockout (UVLO) of power supplies on primary-side ( $V_{DD}$ ), and secondary-side ( $V_{CC}$ ).

### Under-Voltage Lockout Protection V<sub>DD</sub> and V<sub>CC</sub>

The NCV51152 provides the Under-Voltage Lockout (UVLO) protection function for  $V_{DD}$  in primary-side and gate drive output for  $V_{CC}$  in secondary-side as shown in Figure 46. The gate driver is running when the  $V_{DD}$  supply voltage is greater than the specified under-voltage lockout threshold voltage (e.g. typically 2.8 V).

In addition, gate output driver has an under-voltage lockout protection (UVLO) function in secondary-side. (e.g.  $V_{\rm CC}$ ).

The variant A and B need to be greater than specified UVLO threshold level with respect to  $V_{EE}$  and GND2 respectively to let the output operate per input signal. The typical  $V_{CC}$  UVLO threshold voltage levels for each option respectively as are per Table 1.

Table 1. V<sub>CC</sub> UVLO OPTION TABLE

	V <sub>CC</sub> UVLO	V <sub>CC</sub> UVLO		
Option	Threshold	Variant A	Variant B	Unit
5-V	6.0	$V_{EE}$	GND2	V
8–V	8.7	$V_{EE}$	GND2	V
12-V	12	$V_{EE}$	GND2	V
17-V	17	$V_{EE}$	GND2	V

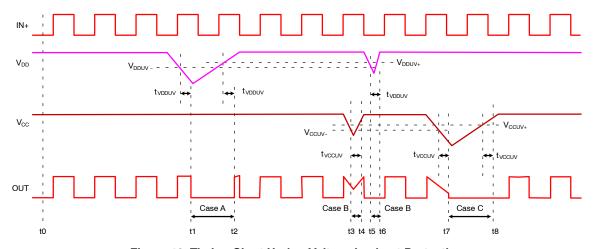


Figure 46. Timing Chart Under-Voltage Lockout Protection

#### Power-up V<sub>CC</sub> UVLO Delay to OUTPUT

To provide a variety of Under-Voltage Lockout (UVLO) thresholds NCV51152 has a power-up delay time during initial VCC start-up or after POR event.

Before the gate driver is ready to deliver a proper output state, there is a power–up delay time from the  $V_{CC}$  power–on reset (POR) threshold to output and it is defined as  $t_{VPOR\ to\ OUT}$ . (e.g. typically18  $\mu s$ ). Figure 47 shows the  $V_{CC}$  power–up UVLO delay time diagram.

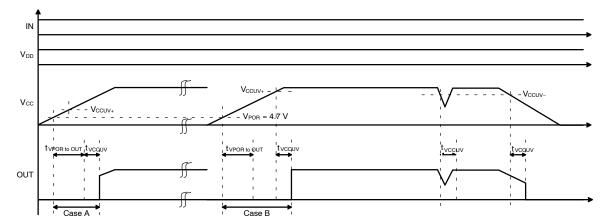


Figure 47. V<sub>CC</sub> Power-up UVLO Delay Time

#### **FUNCTIONAL MODES TABLE**

Table 2 and Table 3 shows the functional modes for the NCV51152 variant A and B assuming  $V_{DD}$  and  $V_{CC}$  are in the recommended range.

Table 2. FUNCTIONAL MODES FOR THE VARIANT A

Inp	out	Gate Drive Output		
IN+	IN-	OUTH	OUTL	
LOW	X (Note 18)	Hi–Z	LOW	
X (Note 18)	HIGH	Hi–Z	LOW	
HIGH	LOW	HIGH	Hi–Z	

Table 3. FUNCTIONAL MODES FOR THE VARIANT B

Inp	Gate Drive Output	
IN+	IN-	OUT
LOW	X (Note 18)	LOW
X (Note 18)	HIGH	LOW
HIGH	LOW	HIGH

18.X: Don't care

#### APPLICATION INFORMATION

This section provides application guidelines when using the NCV51152.

#### **Power Supply Recommendations**

The NCV51152 variant A and B are designed to support unipolar or bipolar power supply respectively.

The V<sub>DD</sub> input power supply supports a wide voltage range from 3 V to 20 V and the  $V_{CC}$  output supply supports a voltage range from 6.5 V to 30 V. The V<sub>CC</sub> local bypass capacitor should be placed between the V<sub>CC</sub> and V<sub>EE</sub> pins with a value of at least ten times the gate capacitance, and an additional capacitor 100-nF in parallel for device biasing and both capacitors located as close to the device as possible. A low ESR, ceramic surface mount capacitors are recommended. In additional, for the negative bias supply capacitor should be placed between GND2 and V<sub>EE</sub> pins with a value of at least few hundred nanofarads. (variant B). Similarly, the V<sub>DD</sub> bypass capacitor should also be placed between the V<sub>DD</sub> and GND1 pins for input logic power supply. We recommend using 2 capacitors; at least 100 nF ceramic surface-mount capacitor with few microfarads added in parallel and both capacitors also located as close to the pins of the device as shown in Figure 48.

 In Unipolar power supply the driver is typically supplied with a positive voltage at V<sub>CC</sub>. For operation with unipolar supply, the V<sub>CC</sub> supply is connected to 15 V with respect to V<sub>EE</sub> pin for IGBTs and MOSFET, and 20 V for SiC MOSFETs. (variant A)  In bipolar power supply the driver is typically supplied of the V<sub>CC</sub> and V<sub>EE</sub> output supplies for bipolar operation are 15 V and –8 V with respect to GND2 for IGBTs and 20 V and –5 V for SiC MOSFETs. Negative power supply prevents the power device from unintentionally turning on because of current induced from the Miller effect. (variant B)

#### **Input Stage**

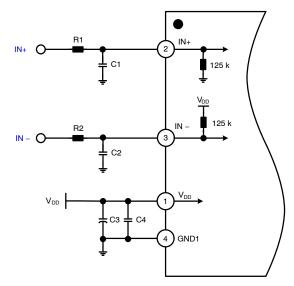


Figure 48. Schematic of Input Stage

The input signal pins (IN+, and IN-) of the NCV51152 are based on the TTL compatible input-threshold logic that is independent of the V<sub>DD</sub> supply voltage.

The logic level compatible input provides a typically HIGH and LOW threshold of 1.6 V and 1.1 V respectively. The input signal pins impedance is 125 k $\Omega$  typically and the IN+ pin is pulled to GND1 pin and IN- pin is pulled to V<sub>DD</sub> pin as shown in Figure 48. For non-inverting input logic input signal is applied to IN+ while the IN- input can be used as an enable function. If IN- is pulled HIGH, the driver output remains LOW state, regardless of the state of IN+. To enable the driver output, IN- should be tied to GND1 through a few ten k $\Omega$  resistor (e.g.10 k $\Omega$ ) or can be used as an active LOW enable pull down.

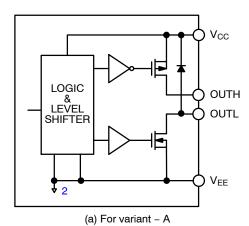
- Non-inverting input IN+ controls the driver output while inverting input IN- is set to LOW
- Inverting input IN- controls the driver output while non-inverting input IN+ is set to HIGH

An RC filter is recommended to be added on the input signal pins to reduce the impact of system noise and ground bounce, the time constant of the RC filter as shown in Figure 48. Such a filter should use an  $R_{IN}$  in the range of 0  $\Omega$  to 100  $\Omega$  and a  $C_{IN}$  between 10 pF and 100 pF.

#### **Output Stage**

The NCV51152 have different output stages of the variant A and B as shown in Figure 49.

For the variant A is designed to support separate source (OUTH) and sink (OUTL) outputs. This scheme allows a single resistor between each pin and the MOSFET gate to independently control gate ringing as well as fine tuning  $dV_{DS}/dT$  turn–on and turn–off transitions present on the MOSFET drain–source voltage.



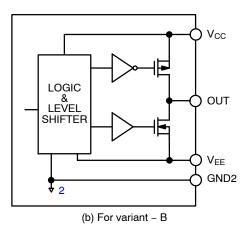
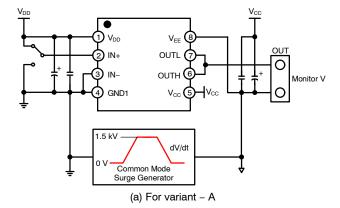


Figure 49. Schematic of Output Stage

The output impedance of the pull up and pull down switches shall be able to provide about +4.5 A and -9 A peak currents typical at 25°C and the minimum sink and source peak currents are -7 A sink and +2.6 A source at 125°C.

#### **Common Mode Transient Immunity Testing**

Figure 50 shows a simplified diagram of the Common Mode Transient Immunity (CMTI) testing configuration for each the variant A and B. CMTI is the maximum sustainable common–mode voltage slew rate while maintaining the correct output. CMTI applies to both rising and falling common–mode voltage edges. CMTI is tested with the transient generator connected between GND1 and  $V_{\rm EE}$ . ( $V_{\rm CM}=1500~{\rm V}$ ).



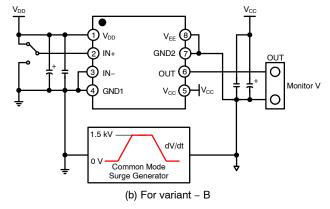


Figure 50. Common Mode Transient Immunity Test Circuit

#### **PCB Layout Guideline**

To improve the switching characteristics and efficiency of design, the following should be considered before beginning a PCB layout.

#### Component Placement

- Keep the input/output traces as short as possible.
   Minimize influence of the parasitic inductance and capacitance on the layout. (To maintain low signal-path inductance, avoid using via.)
- Placement and routing for supply bypass capacitors for V<sub>DD</sub>, V<sub>CC</sub> and V<sub>EE</sub>, and gate resistors need to be located as close as possible to the gate driver.
- The gate driver should be located switching device as close as possible to decrease the trace inductance and avoid output ringing.

#### **Grounding Consideration**

 Have a solid ground plane underneath the high-speed signal layer.

#### High-Voltage (VISO) Consideration

 To ensure isolation performance between the primary and secondary side, any PCB traces or copper should be not placed under the driver device as shown in Figure 51.
 A PCB cutout is recommended to avoid contamination that may impair the isolation performance of NCV51152.

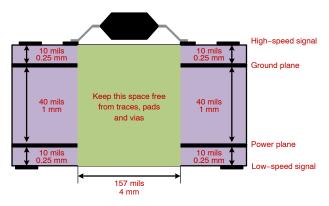


Figure 51. Recommended Layer Stack

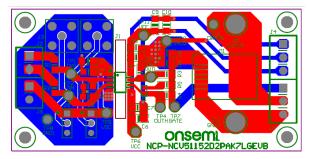
Figure 52 shows the 3D layout of the top view of an evaluation board. The component's location of the PCB

cutout between primary and secondary sides ensures isolation performance.

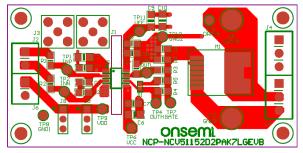


Figure 52. 3-D PCB View

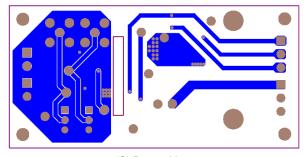
Figure 53 shows the top and bottom layer traces and copper of printed circuit board layout.



(A) Top & Bottom View



(B) Top View



(C) Bottom View

Figure 53. Printed Circuit Board

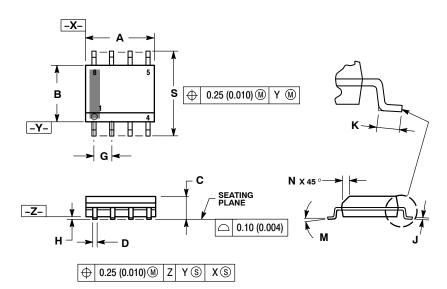
# **ORDERING INFORMATION**

Device	Description	Package	UVLO	OUTPUT/UVLO/NEG	Shipping <sup>†</sup>
NCV51152AADR2G*	High current single isolated MOS driver	SOIC-8 NB (Pb - Free)	6 V	Split OUTPUT	2500 / Tape & Reel
NCV51152BADR2G		SOIC-8 NB (Pb - Free)	8 V		2500 / Tape & Reel
NCV51152CADR2G		SOIC-8 NB (Pb - Free)	12 V		2500 / Tape & Reel
NCV51152DADR2G*		SOIC-8 NB (Pb - Free)	17 V		2500 / Tape & Reel
NCV51152ABDR2G*	High current single isolated MOS driver with true VCC UVLO	SOIC-8 NB (Pb - Free)	6 V	TRUE VCC UVLO	2500 / Tape & Reel
NCV51152BBDR2G*		SOIC-8 NB (Pb - Free)	8 V		2500 / Tape & Reel
NCV51152CBDR2G*		SOIC-8 NB (Pb - Free)	12 V		2500 / Tape & Reel
NCV51152DBDR2G*		SOIC-8 NB (Pb-Free)	17 V		2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.
\*Option on demand

#### **PACKAGE DIMENSIONS**

#### SOIC-8 NB CASE 751-07 **ISSUE AK**

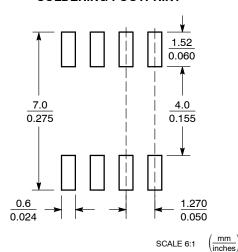


- NOTES:
  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  2. CONTROLLING DIMENSION: MILLIMETER.

- CONTROLLING DIMENSION: MILLIMETER. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
  MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
  DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
  751-01 THRUIT 751-06 ARE ORSOLETE NEW
- 751–01 THRU 751–06 ARE OBSOLETE. NEW STANDARD IS 751–07.

	MILLIN	IETERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the onsemi Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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